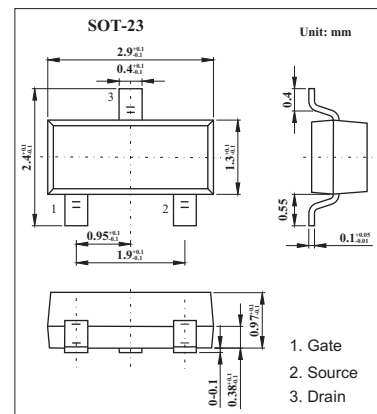


## HEXFET Power MOSFET

## KRLML6402

## ■ Features

- Ultra low on-resistance.
- P-Channel MOSFET.
- SOT-23 Footprint.
- Low profile(<1.1mm).
- Available in tape and reel.
- Fast switching.

■ Absolute Maximum Ratings  $T_a = 25^\circ\text{C}$ 

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	-20	V
Gate-to-source voltage	$V_{GS}$	$\pm 12$	V
Continuous drain current, $V_{GS}@-4.5V$ , $T_A=25^\circ\text{C}$	$I_D$	-3.7	A
Continuous drain current, $V_{GS}@-4.5V$ , $T_A=70^\circ\text{C}$		-2.2	
Pulsed drain current *1	$I_{DM}$	-22	A
Power dissipation @ $T_A=25^\circ\text{C}$	$P_D$	1.3	W
Power dissipation @ $T_A=70^\circ\text{C}$		0.8	
Linear derating factor		0.01	mW/ $^\circ\text{C}$
Single Pulse Avalanche Energy *2	$E_{AS}$	11	MJ
Maximum Junction-to-Ambient *3	$R_{\theta JA}$	100	$^\circ\text{C}/\text{W}$
Junction and storage temperature range	$T_J, T_{STG}$	-55 to +150	$^\circ\text{C}$

\*1Reptitive rating:pulse width limited by max.junction temperature.

\*2. Starting  $T_J=25^\circ\text{C}$ ,  $L=1.65\text{mH}$ ,  $R_G=25\ \Omega$ ,  $I_{AS}=-3.7\text{A}$ .

\*3.Surface mounted on 1"square single layer 1oz.copper FR4 board,steady state.

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## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
Drain-source Breakdown voltage	V <sub>DSS</sub>	I <sub>D</sub> = -250 μA, V <sub>GS</sub> = 0V	-20			V
Gate-source leakage current	I <sub>DSS</sub>	V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0V			-1.0	μA
		V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 70°C			-25	
Gate-source leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ±12V			±100	nA
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-0.40	-0.55	-0.95	V
Static drain-source on- resistance	R <sub>DS(on)</sub>	I <sub>D</sub> = -3.7A, V <sub>GS</sub> = -4.5V		0.050	0.065	Ω
		I <sub>D</sub> = -3.1A, V <sub>GS</sub> = -2.5V		0.080	0.0135	
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -3.7 A	6.0			S
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> = -10 V,		633		pF
Output capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V,		145		
Reverse transfer capacitance	C <sub>rss</sub>	f = 1MHz		110		
Total Gate Charge	Q <sub>g</sub>			8.0	12	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> = -10V, V <sub>GS</sub> = -5.0 V, I <sub>D</sub> = -3.7 A		1.2	1.8	
Gate-Drain Charge	Q <sub>gd</sub>			2.8	4.2	
Turn-on delay time	t <sub>d(on)</sub>	I <sub>D</sub> = -3.7 A,		350		ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> = -10 V,		48		
Turn-off delay time	t <sub>d(off)</sub>	R <sub>D</sub> = 2.7 Ω		588		
Fall time	t <sub>f</sub>	R <sub>G</sub> = 89 Ω		381		
Reverse recovery time	t <sub>rr</sub>	T <sub>J</sub> = 25°C, I <sub>F</sub> = -1.0 A,		29	43	ns
Reverse recovery charge	Q <sub>rr</sub>	di / dt = -100 A/μs *2		11	17	nC
Continuous source current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p-n junction diode			-1.3	A
Pulsed source current *1	I <sub>SM</sub>				-22	
Diode forward voltage	V <sub>SD</sub>	T <sub>J</sub> = 25°C, V <sub>GS</sub> = 0 V, I <sub>S</sub> = -1.0 A *2			-1.2	V

\*1 Repetitive rating; pulse width limited by max. junction temperature.

\*2 Pulse width ≤ 300 μs, Duty cycle ≤ 2%